

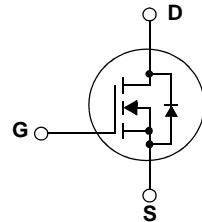
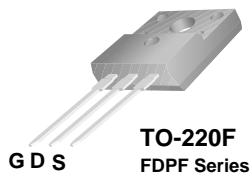
# FDP7N50F / FDPF7N50F

## N-Channel MOSFET, FRFET

### 500V, 6A, 1.15Ω

#### Features

- $R_{DS(on)} = 0.95\Omega$  (Typ.) @  $V_{GS} = 10V$ ,  $I_D = 3A$
- Low gate charge (Typ. 15nC)
- Low  $C_{rss}$  (Typ. 6.3pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS compliant



#### Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.

#### MOSFET Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted\*

Symbol	Parameter		FDP7N50F	FDPF7N50F	Units
$V_{DSS}$	Drain to Source Voltage		500		V
$V_{GSS}$	Gate to Source Voltage			$\pm 30$	V
$I_D$	Drain Current	-Continuous ( $T_C = 25^\circ C$ )	6	6*	A
		-Continuous ( $T_C = 100^\circ C$ )	3.6	3.6*	
$I_{DM}$	Drain Current	- Pulsed	(Note 1)	24	24*
$E_{AS}$	Single Pulsed Avalanche Energy		(Note 2)	270	mJ
$I_{AR}$	Avalanche Current	(Note 1)		6	A
$E_{AR}$	Repetitive Avalanche Energy		(Note 1)	20	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	4.5	V/ns
$P_D$	Power Dissipation	( $T_C = 25^\circ C$ )	200	38.5	W
		- Derate above $25^\circ C$	1.59	0.3	$W/^\circ C$
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range			-55 to +150	$^\circ C$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	$^\circ C$

\*Drain current limited by maximum junction temperature

#### Thermal Characteristics

Symbol	Parameter	FDP7N50F	FDPF7N50F	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	4.0	$^\circ C/W$
$R_{\theta CS}$	Thermal Resistance, Junction to Ambient	0.5	-	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

## Package Marking and Ordering Information $T_C = 25^\circ\text{C}$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP7N50F	FDP7N50F	TO-220	-	-	50
FDPF7N50F	FDPF7N50F	TO-220F	-	-	50

## Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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### Off Characteristics

$\text{BV}_{\text{DSS}}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	500	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}, \text{Referenced to } 25^\circ\text{C}$	-	0.5	-	$^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}, V_{GS} = 0\text{V}$	-	-	10	$\mu\text{A}$
$I_{\text{GSS}}$	Gate to Body Leakage Current	$V_{GS} = \pm 30\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA

### On Characteristics

$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	3.0	-	5.0	V
$R_{DS(\text{on})}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 3\text{A}$	-	0.95	1.15	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40\text{V}, I_D = 3\text{A}$ (Note 4)	-	4.3	-	S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	720	960	pF
$C_{oss}$	Output Capacitance		-	85	115	pF
$C_{rss}$	Reverse Transfer Capacitance		-	6.3	10	pF
$Q_{q(\text{tot})}$	Total Gate Charge at 10V	$V_{DS} = 400\text{V}, I_D = 6\text{A}$ $V_{GS} = 10\text{V}$ (Note 4, 5)	-	15	20	nC
$Q_{qs}$	Gate to Source Gate Charge		-	4.5	-	nC
$Q_{qd}$	Gate to Drain "Miller" Charge		-	6	-	nC

### Switching Characteristics

$t_{d(\text{on})}$	Turn-On Delay Time	$V_{DD} = 250\text{V}, I_D = 6\text{A}$ $R_G = 25\Omega$ (Note 4, 5)	-	17	45	ns
$t_r$	Turn-On Rise Time		-	30	70	ns
$t_{d(\text{off})}$	Turn-Off Delay Time		-	35	80	ns
$t_f$	Turn-Off Fall Time		-	20	50	ns

### Drain-Source Diode Characteristics

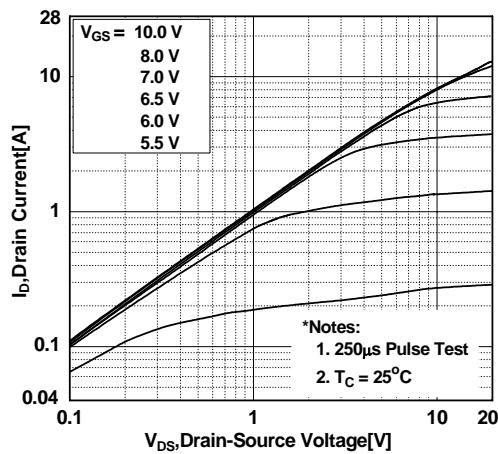
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	6	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	24	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 6\text{A}$	-	-	1.5	
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 6\text{A}$	-	85	-	
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt = 100\text{A}/\mu\text{s}$	(Note 4)	-	0.15	$\mu\text{C}$

#### Notes:

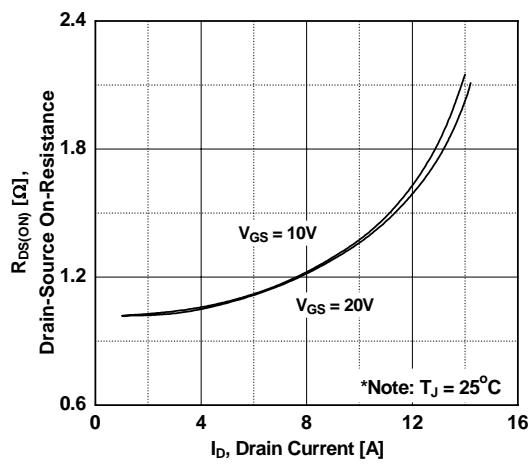
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. L = 13mH,  $I_{AS} = 6\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 6\text{A}$ ,  $dI/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq \text{BV}_{\text{DSS}}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

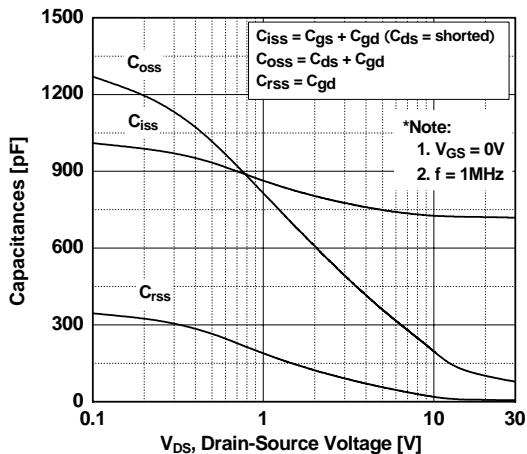
**Figure 1. On-Region Characteristics**



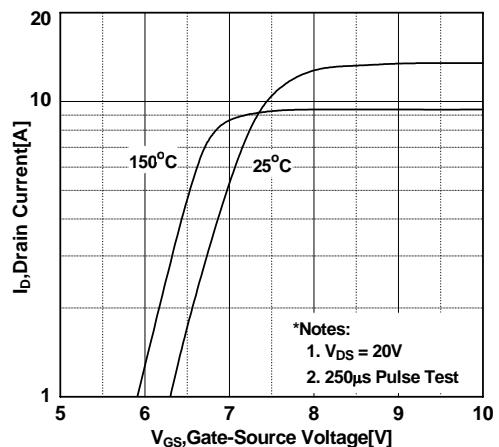
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



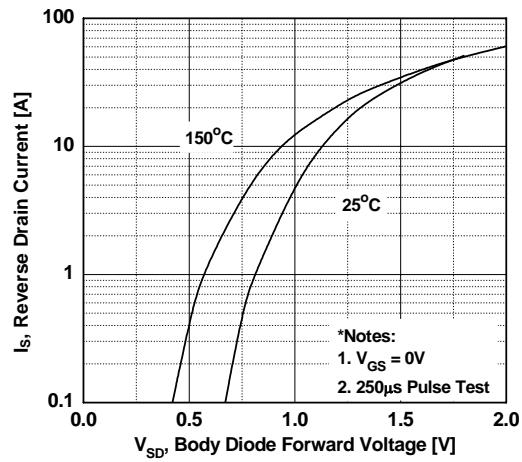
**Figure 5. Capacitance Characteristics**



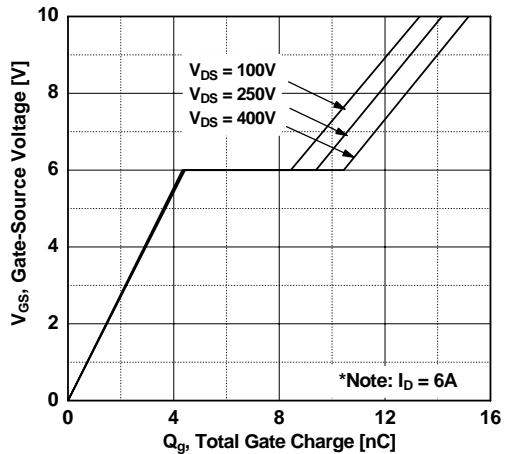
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

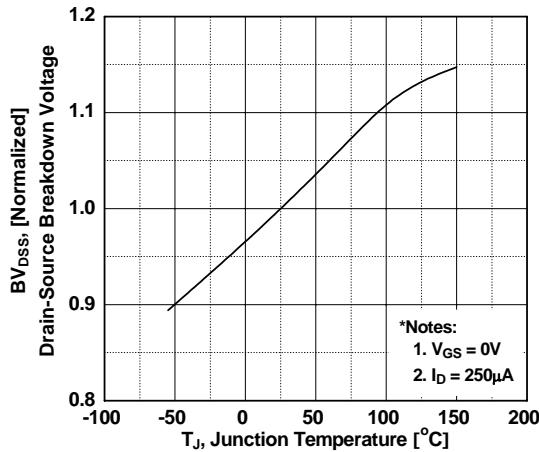


**Figure 6. Gate Charge Characteristics**

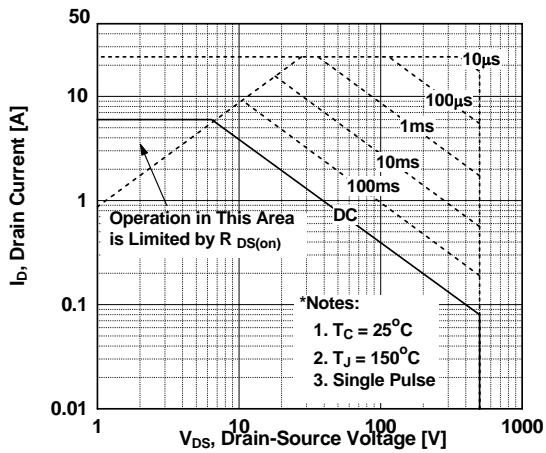


## Typical Performance Characteristics (Continued)

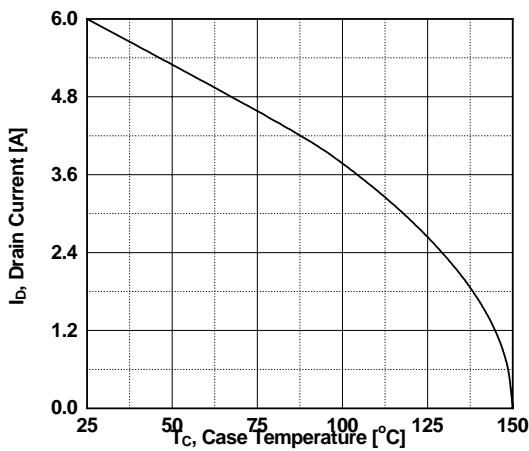
**Figure 7. Breakdown Voltage Variation vs. Temperature**



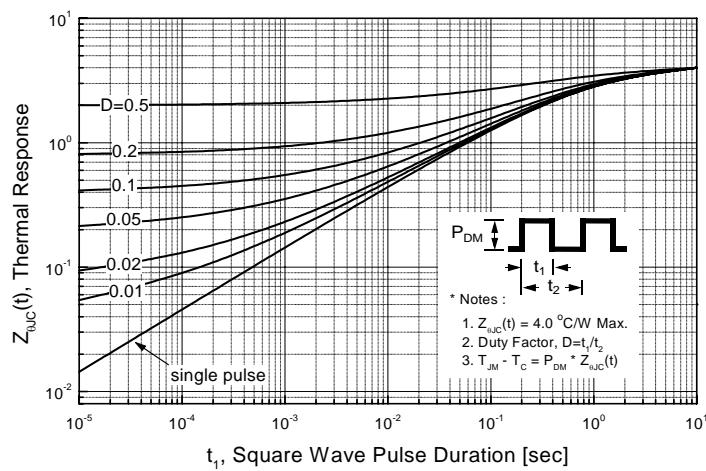
**Figure 8. Maximum Safe Operating Area - FDPF7N50F**



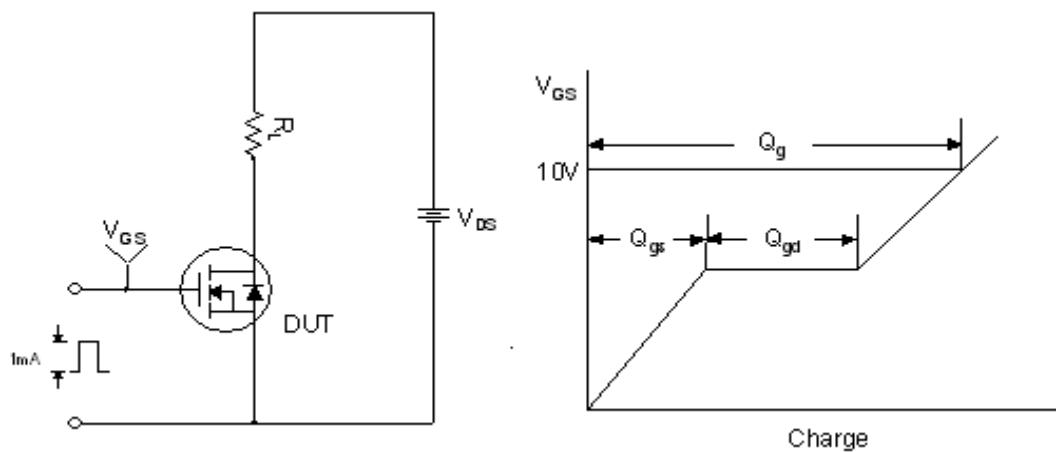
**Figure 9. Maximum Drain Current vs. Case Temperature - FDPF7N50F**



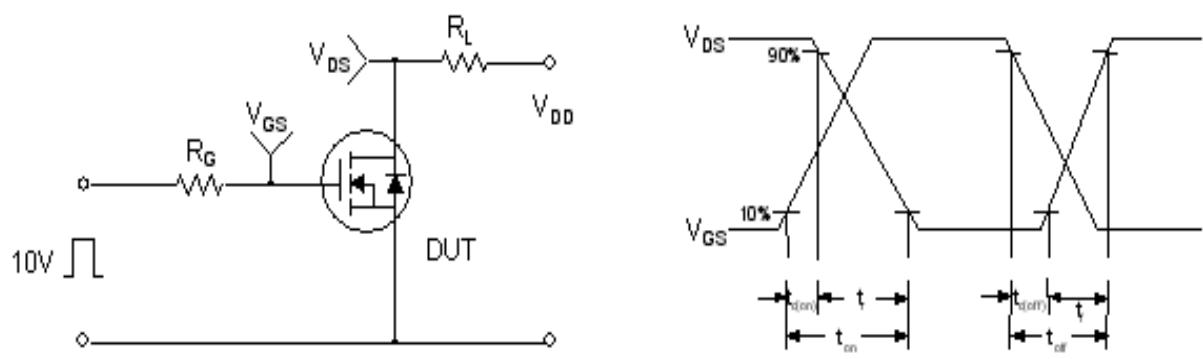
**Figure 10. Transient Thermal Response Curve - FDPF7N50F**



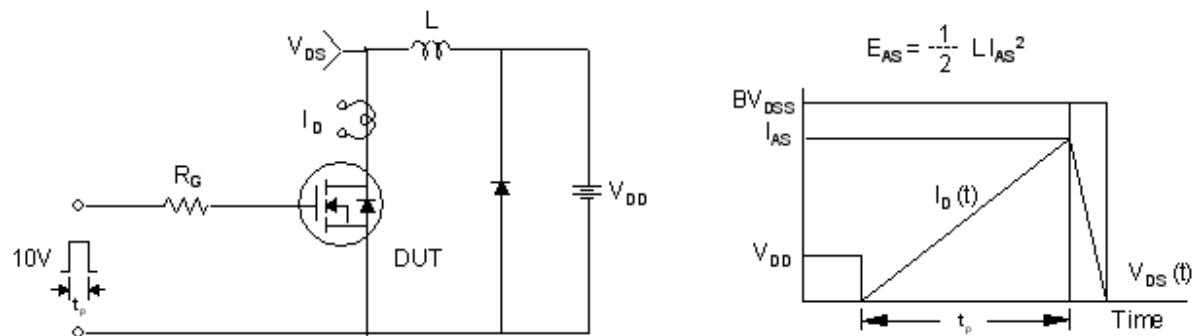
**Gate Charge Test Circuit & Waveform**



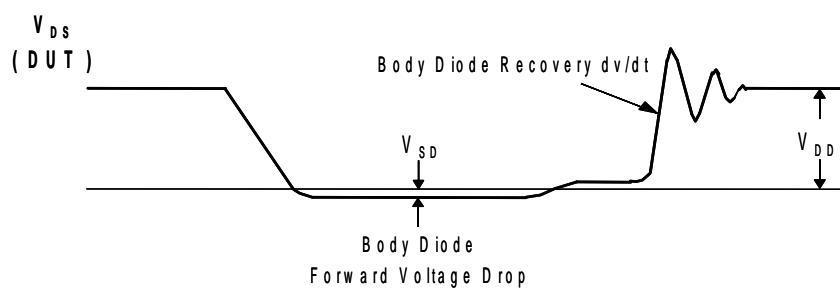
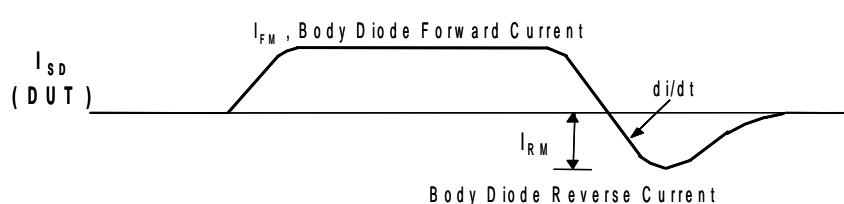
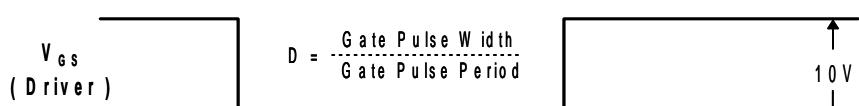
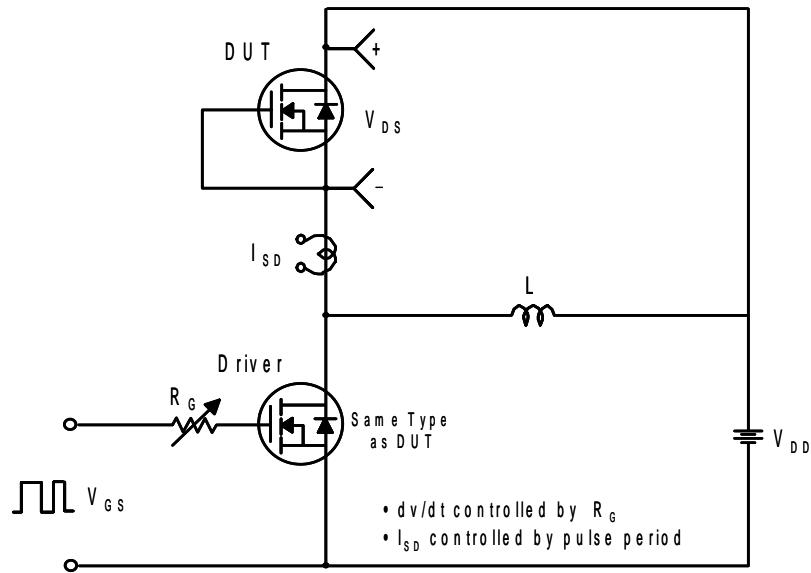
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**

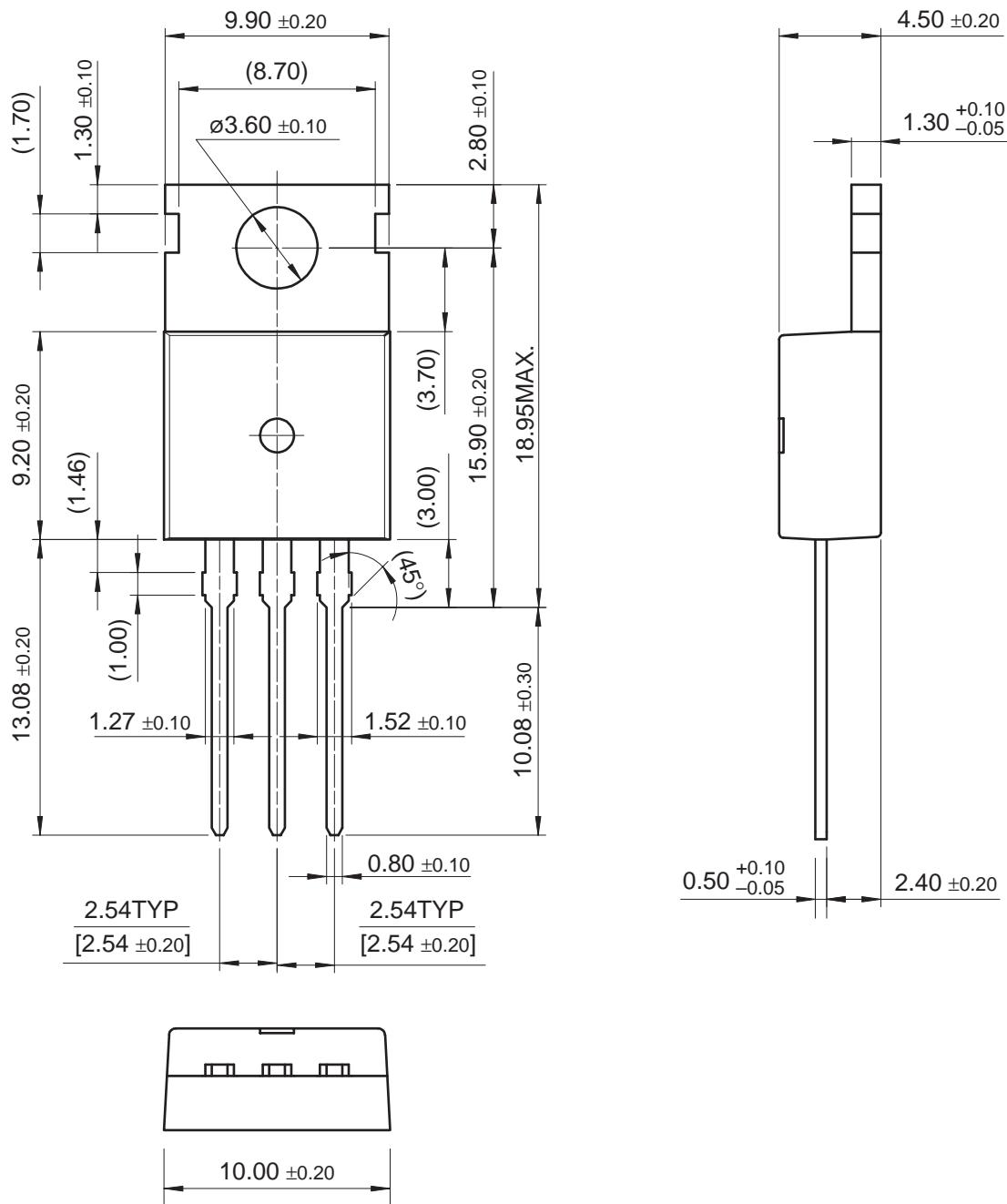


**Peak Diode Recovery dv/dt Test Circuit & Waveforms**



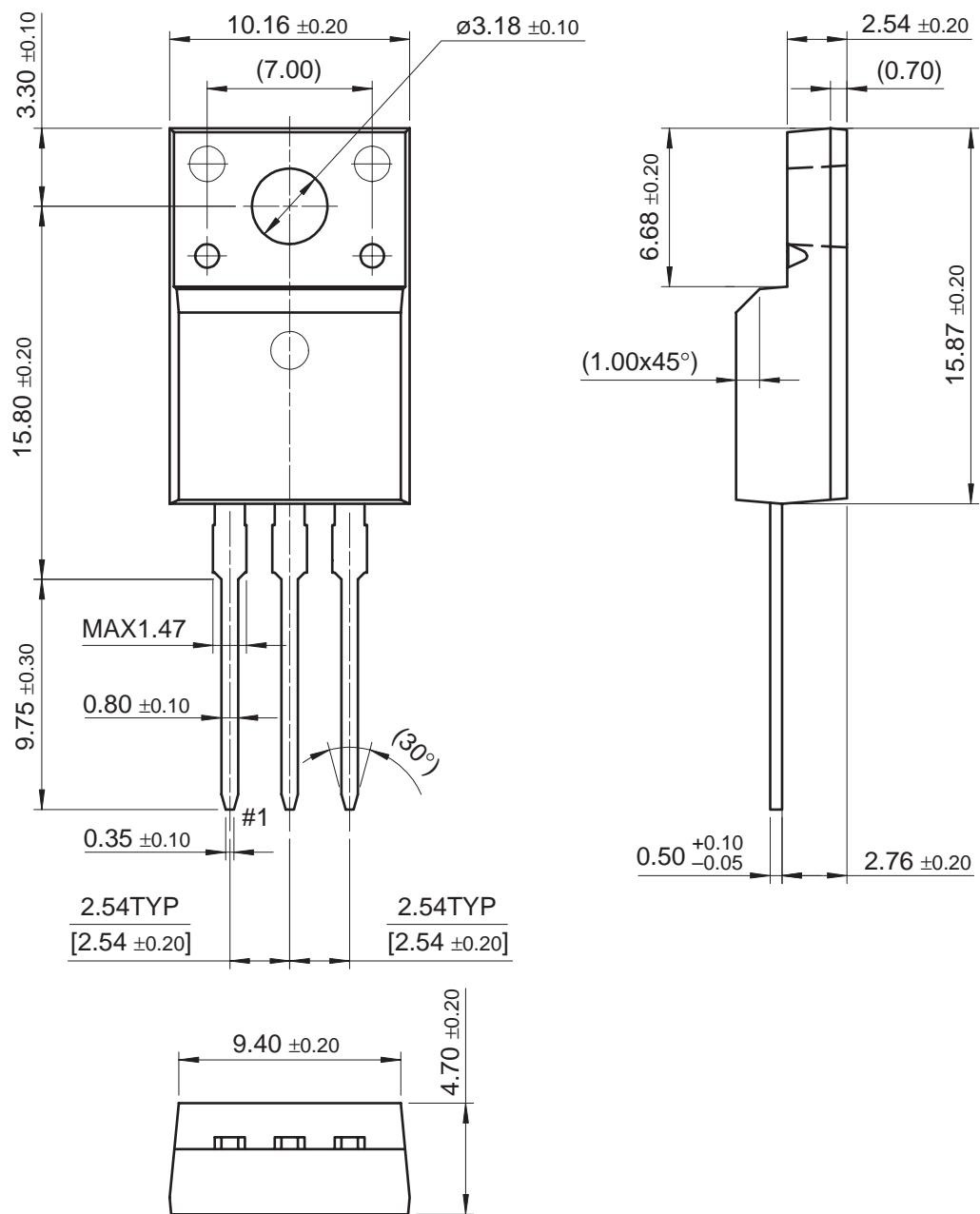
## Mechanical Dimensions

TO-220



## Mechanical Dimensions

TO-220F



Dimensions in Millimeters



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